

#### 12500 TI Boulevard, MS 8640, Dallas, Texas 75243

# PCN# 20170216000A Qualification of NFME as an additional Assembly & Test site for select devices Change Notification / Sample Request

**Date:** March 28, 2017

To: TOKYO ELECTRON DEVICE (DSTR) PCN

#### Dear Customer:

Revision A is to announce the <u>addition</u> of new devices that were not included on the original PCN notification.

This is an announcement of a change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

We request you acknowledge receipt of this notification within **30** days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance of the change. If you require samples or additional data to support your evaluation, please request within 30 days.

The changes discussed within this PCN will not take effect any earlier than **90** days from the date of this notification, unless customer agreement has been reached on an earlier implementation of the change. This notification period is per TI's standard process.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Manager (PCN www admin team@list.ti.com).

Sincerely,

PCN Team SC Business Services

#### 20170216000A Attachment: 1

#### **Products Affected:**

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

**DEVICE** ATL432AIDBZR ATL431AQDBZR ATL431BIDBZR **CUSTOMER PART NUMBER** 

null null null

Technical details of this Product Change follow on the next page(s).

<b>PCN Num</b>	<b>PCN Number:</b> 20170216000A <b>PCN Date:</b> Mar 28, 2017							
Title: Qualification of NFME as an additional Assembly & Test site for select devices								
Customer Contact: PCN Manager Dept: Quality Services								
Estimated Sample Date Provide				Provided a	nt Sample			
Proposed	1 <sup>st</sup> Ship	Date:	June 28, 2	2017	Availability:	requ		p.:0
Change Type:								
✓ Assembly Site   ☐ Design   ☐ Wafer Bump Site								
	mbly Prod				a Sheet		afer Bump	
	mbly Mat				: number change		afer Bump	
	anical Sp				t Site	=-	afer Fab Si	
	ng/Shipp	ing/Labe	eling   L	resi	t Process		<u>/afer Fab M</u> /afer Fab Pr	
				DC	N Details	VV	alei Fab Pi	ocess
Description	on of Ch	ange:		PC	in Details			
			ne addition	of new	v devices that were not	incluc	led on the o	original PCN
					ed and <b>bolded</b> in the			
					be 90 days from this			
devices on	<mark>ly.</mark>							
		_						
					ng the qualification NFN			
Material di				e "Proa	uct Affected" Section.	Curre	nt assembly	y sites and
Material ui	Herences	are as i	ollows.					
Assembl	v Site	Assem	bly Site O	riain	Assembly Country	Code	Assembl	y Site City
ASEV	-	71000111	AWH	· · · · · ·	CHN			eihai
H.OLV				THA		Bangpakong		
	С		NS2		I IHA		Bana	Dakullu l
UTA			NS2 HNT					
	Α		NS2 HNT NFM		THA THA CHN		Ayut	thaya ntong
UTA HAN NFM	A IE		HNT		THA		Ayut	thaya
UTA HAN	A IE		HNT NFM	1	THA CHN		Ayut	thaya ntong
UTA HAN NFM	A IE		HNT		THA CHN	IANA	Ayut	thaya
UTA HAN NFM	A IE Difference	AS	HNT NFM		THA CHN	IANA 00154	Ayut	thaya ntong
UTA HAN NFM Material [	A IE Difference mpound	AS 112	HNT NFM		THA CHN  UTAC H PZ0001 40		Ayut	ntong  NFME
UTA HAN NFM  Material I  Mount con	Difference mpound npound	AS 112	HNT NFM SEWH 0999A1		THA CHN  UTAC H PZ0001 40	00154	Ayut	ntong  NFME A-03
Mount con	Difference mpound npound type	112 402	HNT NFM SEWH 0999A1 0039A1		THA CHN  UTAC H PZ0001 40 CZ0096 45 Au	00154 50179	Ayut	NFME A-03 R-27
Material E  Mount con  Mold con  Wire t  Lead F	Difference mpound npound type Tinish	112 402 Ni	HNT NFM SEWH 0999A1 0039A1 Au	ill rem	THA CHN  UTAC H PZ0001 40 CZ0096 45 Au NiPdAu N	00154 50179 Au iPdAu	Ayut	NFME A-03 R-27 Cu Matte Sn
Material E  Mount con  Mold con  Wire t  Lead F	Difference mpound npound type Tinish	112 402 Ni	HNT NFM SEWH 0999A1 0039A1 Au	ill rem	THA CHN  UTAC H PZ0001 40 CZ0096 45 Au	00154 50179 Au iPdAu	Ayut	NFME A-03 R-27 Cu Matte Sn
Material I  Mount con Mold com Wire t Lead F Test coveratest MQ.	mpound npound type inish age, inse	AS 112 402 Ni	HNT NFM  SEWH 0999A1 0039A1 Au iPdAu onditions w		THA CHN  UTAC H PZ0001 40 CZ0096 45 Au NiPdAu N ain consistent with cur	00154 50179 Au iPdAu rent te	Ayut Nar	NFME A-03 R-27 Cu Matte Sn verified with
Material I  Mount con Mold con Wire t Lead F Test coveratest MQ.	mpound rype ration of	112 402 Niertions, c	HNT NFM  SEWH 0999A1 0039A1 Au iPdAu onditions w	nbine l	THA CHN  UTAC H PZ0001 40 CZ0096 45 Au NiPdAu N ain consistent with cur ead free solutions in a	00154 50179 Au iPdAu rent te	Ayut Nar  Standard	NFME A-03 R-27 Cu Matte Sn verified with
Material I  Mount con Mold con Wire t Lead F Test coveratest MQ.	mpound rype ration of	112 402 Niertions, c	HNT NFM  SEWH 0999A1 0039A1 Au iPdAu onditions w	nbine l	THA CHN  UTAC H PZ0001 40 CZ0096 45 Au NiPdAu N ain consistent with cur	00154 50179 Au iPdAu rent te	Ayut Nar  Standard	NFME A-03 R-27 Cu Matte Sn verified with
Mount con Mold com Wire t Lead F Test covers test MQ. Upon expir	mpound repound	Niertions, cothis PCN	HNT NFM  SEWH 0999A1 0039A1 Au iPdAu onditions w	nbine l <mark>?</mark> – car	THA CHN  UTAC H PZ0001 40 CZ0096 49 Au NiPdAu N ain consistent with cure ead free solutions in a m ship with both Matter	00154 50179 Au iPdAu rent te single Sn and	Ayut Nar  Pesting and versiting and versitin	NFME A-03 R-27 Cu Matte Sn verified with
Material I  Mount con Mold com Wire t Lead F Test coveratest MQ.  Upon expir	mpound rype inish age, inse	Niertions, cothis PCN ple; TL4	HNT NFM  SEWH 0999A1 0039A1 Au iPdAu onditions w	nbine l <mark>?</mark> – car	THA CHN  UTAC H PZ0001 40 CZ0096 45 Au NiPdAu N ain consistent with cur ead free solutions in a	00154 50179 Au iPdAu rent te single Sn and	Ayut Nar  Pesting and versiting and versitin	NFME A-03 R-27 Cu Matte Sn verified with
Mount con Mold com Wire t Lead F Test covers test MQ. Upon expir	mpound rype inish age, inse	Niertions, cothis PCN ple; TL4	HNT NFM  SEWH 0999A1 0039A1 Au iPdAu onditions w	nbine l <mark>?</mark> – car	THA CHN  UTAC H PZ0001 40 CZ0096 49 Au NiPdAu N ain consistent with cure ead free solutions in a m ship with both Matter	00154 50179 Au iPdAu rent te single Sn and	Ayut Nar  Pesting and versiting and versitin	NFME A-03 R-27 Cu Matte Sn verified with
Material I  Mount con Mold com Wire t  Lead F  Test coveratest MQ.  Upon expir number, f  When avai	mpound repound ration of or exam lable cus	Niertions, cothis PCN ple; TL4	HNT NFM  SEWH 0999A1 0039A1 Au iPdAu onditions w	nbine l <mark>?</mark> – car	THA CHN  UTAC H PZ0001 40 CZ0096 49 Au NiPdAu N ain consistent with cure ead free solutions in a m ship with both Matter	00154 50179 Au iPdAu rent te single Sn and	Ayut Nar  Pesting and versiting and versitin	NFME A-03 R-27 Cu Matte Sn verified with
Material I  Mount con Mold com Wire t  Lead F  Test covere test MQ.  Upon expir number, f  When avai TL431ACI  Reason for	mpound repound	Niertions, cothis PCN ple; TL4	HNT NFM  SEWH 0999A1 0039A1 Au iPdAu onditions w	nbine l <mark>?</mark> – car	THA CHN  UTAC H PZ0001 40 CZ0096 49 Au NiPdAu N ain consistent with cure ead free solutions in a m ship with both Matter	00154 50179 Au iPdAu rent te single Sn and	Ayut Nar  Pesting and versiting and versitin	NFME A-03 R-27 Cu Matte Sn verified with
Material I  Mount con Mold com Wire to Lead F Test covers test MQ.  Upon expir number, f  When avai TL431ACI  Reason for Continuity	mpound repound	Niertions, cothis PCN ple; TL4	HNT NFM  SEWH 0999A1 0039A1 Au iPdAu onditions w , TI will con 31ACDBZF	nbine I R – car NiPdA	THA CHN  UTAC H PZ0001 40 CZ0096 45 Au NiPdAu N ain consistent with cur ead free solutions in a n ship with both Matte	00154 50179 Au iPdAu rent te single Sn and	Ayut Nar Nar Standard NiPdAu.	NFME A-03 R-27 Cu Matte Sn verified with
Material I  Mount con Mold con Wire t Lead F Test covere test MQ.  Upon expir number, f When avai TL431ACI Reason for Continuity Anticipate	mpound repound	Niertions, cothis PCN ple; TL4	HNT NFM  SEWH 0999A1 0039A1 Au iPdAu onditions w , TI will con 31ACDBZF	nbine I R – car NiPdA	THA CHN  UTAC H PZ0001 40 CZ0096 49 Au NiPdAu N ain consistent with cure ead free solutions in a m ship with both Matter	00154 50179 Au iPdAu rent te single Sn and	Ayut Nar Nar Standard NiPdAu.	NFME A-03 R-27 Cu Matte Sn verified with
Material I  Mount con Mold com Wire to Lead F Test covers test MQ.  Upon expir number, f  When avai TL431ACI  Reason for Continuity Anticipate None	mpound repound	Niertions, cothis PCN ple; TL4 tomers r	HNT NFM  SEWH 0999A1 0039A1 Au iPdAu onditions w  , TI will con 31ACDBZF may specify	nbine I R – car NiPdA	THA CHN  UTAC H PZ0001 40 CZ0096 45 Au NiPdAu N ain consistent with cur ead free solutions in a a ship with both Matte	00154 50179 Au iPdAu rent te single Sn and	Ayut Nar Nar Standard NiPdAu.	NFME A-03 R-27 Cu Matte Sn verified with
Material I  Mount con Mold com Wire to Lead F Test coveratest MQ.  Upon expir number, f When avai TL431ACI Reason for Continuity Anticipate None	mpound repound	Ni 112 402 Ni ertions, c this PCN ple; TL4 tomers r	HNT NFM  SEWH 0999A1 0039A1 Au iPdAu onditions w  , TI will con 31ACDBZF may specify	nbine I C – car NiPdA	THA CHN  UTAC PZ0001 40 CZ0096 41 Au NiPdAu NiPdAu NipdAu ain consistent with cur ead free solutions in a ship with both Matte au finish by ordering the	iPdAu rent te single Sn and e part	Ayut Nar  Nar  Standard I NiPdAu.  with the Garage	NFME A-03 R-27 Cu Matte Sn verified with  part  suffix, e.g.
Material I  Mount con Mold com Wire to Lead F Test covere test MQ.  Upon expir number, f  When avai TL431ACI  Reason for Continuity Anticipate None Anticipate	mpound repound	Ni 112 402 Ni rtions, c this PCN ple; TL4 tomers r  ct on Fo o the	HNT NFM  SEWH 0999A1 0039A1 Au iPdAu onditions w  , TI will con 31ACDBZF may specify  orm, Fit, Fu	nbine I C - car NiPdA Inction Claration	THA CHN  UTAC H PZ0001 40 CZ0096 45 Au NiPdAu N ain consistent with cur ead free solutions in a a ship with both Matte	oo154 50179 Au iPdAu rent te single Sn and e part	Ayut Nar  Nar  Standard I NiPdAu.  with the G4	NFME A-03 R-27 Cu Matte Sn Verified with  Part  Suffix, e.g.  egative):

	obtained from the <u>TI Eco-Info website</u> . There is no impact to the
	material meeting current regulatory compliance requirements
	with this PCN change.

#### **Changes to product identification resulting from this PCN:**

Assembly Site			
ASEWH	Assembly Site Origin (22L)	ASO: AWH	ECAT:G4
UTAC	Assembly Site Origin (22L)	ASO: NS2	ECAT:G4
HANA	Assembly Site Origin (22L)	ASO: HNT	ECAT:G4
NFME	Assembly Site Origin (22L)	ASO: NFM	ECAT:G3

Sample product shipping label (not actual product label)

ECAT: G4 = NiPdAu ECAT: G3 = Matte Sn

TEXAS INSTRUMENTS MADE IN: Malaysia 2DC: 20:

2DC: 2Q:
MSL '2 /260C/1 YEAR SEAL DT
MSL 1 /235C/UNLIM 03/29/04

OPT: ITEM:

LBL: 5A (L)TO:1750

(1P) \$N74L\$07N\$R (Q) 2000 (D) 033(

(31T)LOT: 3959047MLA (4W) TKY(1T) 7523483SI2

(P) (2P) REV: (V) 0033317 (20L) CSO: SHE (21L) CCO:USA (22L) ASO: MLA (23L) ACO: MYS

ASSEMBLY SITE CODES: AWH= I, NS2= B, HNT= H, NFM= E

#### **Product Affected:**

ATL431AIDBZR	LM4040D20QDBZT	TL4050B25IDBZT	TL431LACDBZR-ND
ATL431AQDBZR	LM4040D25IDBZR	TL4050B25QDBZR	TL431QDBZR
ATL431BIDBZR	LM4040D25IDBZT	TL4050B41IDBZR	TL431QDBZT
ATL431BQDBZR	LM4040D25QDBZR	TL4050B41IDBZT	TL432ACDBZR
ATL432AIDBZR	LM4040D25QDBZT	TL4050B41QDBZR	TL432ACDBZT
ATL432AQDBZR	LM4040D30IDBZR	TL4050B41QDBZT	TL432AIDBZR
ATL432BIDBZR	LM4040D30IDBZT	TL4050B50IDBZR	TL432AIDBZT
ATL432BIDBZR-S	LM4040D30QDBZR	TL4050B50IDBZT	TL432AQDBZR
ATL432BQDBZR	LM4040D41IDBZR	TL4050B50QDBZR	TL432AQDBZT
LM4040A10IDBZR	LM4040D41IDBZT	TL4050B82IDBZT	TL432BCDBZR
LM4040A10IDBZT	LM4040D50IDBZR	TL4050B82QDBZT	TL432BCDBZT
LM4040A20IDBZR	LM4040D50IDBZT	TL4050C10IDBZR	TL432BIDBZR
LM4040A20IDBZT	LM4040D50QDBZR	TL4050C10IDBZT	TL432BIDBZT
LM4040A25IDBZR	LM4040D50QDBZT	TL4050C10QDBZR	TL432BQDBZR
LM4040A25IDBZT	LM4040D82IDBZR	TL4050C20QDBZT	TL432CDBZR
LM4040A30IDBZR	LM4040D82IDBZT	TL4050C25IDBZR	TL432IDBZR
LM4040A30IDBZT	LM4041A12IDBZR	TL4050C25IDBZT	TL432IDBZT
LM4040A41IDBZR	LM4041A12IDBZT	TL4050C25QDBZR	TL432QDBZR
LM4040A41IDBZT	LM4041B12IDBZR	TL4050C41IDBZR	TLV431ACDBZR
LM4040A50IDBZR	LM4041B12IDBZT	TL4050C41IDBZT	TLV431AIDBZR
LM4040A50IDBZT	LM4041BIDBZR	TL4050C41QDBZR	TLV431BCDBZR
LM4040A82IDBZR	LM4041BIDBZT	TL4050C50IDBZR	TLV431BCDBZT
LM4040A82IDBZT	LM4041C12IDBZR	TL4050C50IDBZT	TLV431BIDBZR
LM4040B10IDBZR	LM4041C12IDBZT	TL4050C50QDBZR	TLV431BIDBZT
LM4040B10IDBZT	LM4041C12QDBZR	TL4050C82IDBZT	TLV431BQDBZR

LM4040B20IDBZR	LM4041C12QDBZT	TL4050C82QDBZT	TLV431BQDBZT
LM4040B20IDBZT	LM4041CIDBZR	TL4051A12IDBZR	TLV431CDBZR
LM4040B25IDBZR	LM4041CIDBZT	TL4051A12IDBZT	TLV431IDBZR
LM4040B25IDBZT	LM4041CQDBZR	TL4051A12QDBZR	TLVH431ACDBZR
LM4040B30IDBZR	LM4041CQDBZT	TL4051A12QDBZT	TLVH431ACDBZT
LM4040B30IDBZT	LM4041D12IDBZR	TL4051AIDBZR	TLVH431AIDBZR
LM4040B41IDBZR	LM4041D12IDBZT	TL4051AIDBZT	TLVH431AIDBZT
LM4040B41IDBZT	LM4041D12QDBZR	TL4051AQDBZR	TLVH431AQDBZR
LM4040B50IDBZR	LM4041DIDBZR	TL4051B12IDBZR	TLVH431AQDBZT
LM4040B50IDBZT	LM4041DIDBZT	TL4051B12IDBZT	TLVH431BCDBZR
LM4040B82IDBZR	LM4041DQDBZR	TL4051B12QDBZR	TLVH431BCDBZT
LM4040C10IDBZR	LM4041DQDBZT	TL4051BIDBZR	TLVH431BIDBZR
LM4040C10IDBZT	SNV431BQDBZR	TL4051BIDBZT	TLVH431BIDBZT
LM4040C20IDBZR	TL4050A10IDBZR	TL4051BQDBZR	TLVH431BQDBZR
LM4040C20IDBZT	TL4050A10IDBZT	TL4051C12IDBZR	TLVH431BQDBZT
LM4040C20QDBZR	TL4050A10QDBZR	TL4051C12IDBZT	TLVH431CDBZR
LM4040C20QDBZT	TL4050A20QDBZT	TL4051C12QDBZR	TLVH431CDBZT
LM4040C25IDBZR	TL4050A25IDBZR	TL4051C12QDBZT	TLVH431IDBZR
LM4040C25IDBZT	TL4050A25IDBZT	TL4051CIDBZR	TLVH431IDBZT
LM4040C25QDBZR	TL4050A25QDBZR	TL4051CIDBZT	TLVH431QDBZR
LM4040C25QDBZT	TL4050A25QDBZT	TL4051CQDBZR	TLVH431QDBZT
LM4040C30IDBZR	TL4050A41IDBZR	TL431ACDBZR	TLVH432ACDBZR
LM4040C30IDBZT	TL4050A41IDBZT	TL431ACDBZT	TLVH432ACDBZT
LM4040C30QDBZR	TL4050A41QDBZR	TL431AIDBZR	TLVH432AIDBZR
LM4040C30QDBZT	TL4050A41QDBZT	TL431AIDBZT	TLVH432AQDBZR
LM4040C41IDBZR	TL4050A50IDBZR	TL431AQDBZR	TLVH432AQDBZT
LM4040C41IDBZT	TL4050A50IDBZT	TL431AQDBZT	TLVH432BCDBZR
LM4040C50IDBZR	TL4050A50QDBZR	TL431BCDBZR	TLVH432BIDBZR
LM4040C50IDBZT	TL4050A50QDBZT	TL431BCDBZT	TLVH432BQDBZR
LM4040C50QDBZR	TL4050A82IDBZT	TL431BIDBZR	TLVH432BQDBZT
LM4040C50QDBZT	TL4050A82QDBZT	TL431BIDBZT	TLVH432CDBZR
LM4040C82IDBZR	TL4050B10IDBZR	TL431BQDBZR	TLVH432CDBZT
LM4040D10IDBZR	TL4050B10IDBZT	TL431BQDBZT	TLVH432IDBZR
LM4040D10IDBZT	TL4050B10QDBZR	TL431CDBZR	TLVH432QDBZR
LM4040D20IDBZR	TL4050B10QDBZT	TL431CDBZT	TLVH432QDBZT
LM4040D20IDBZT	TL4050B20QDBZT	TL431IDBZR	
LM4040D20QDBZR	TL4050B25IDBZR	TL431IDBZT	

# **Qualification Report**

NFME SOT: 3DBZ Assy Site Qual --- Cu wire with Au Flash, 150mm wafer, SuHDLF Approve Date 08-Feb-2017

#### **Product Attributes**

Attributes	Qual Device: LM4040C50IDBZR	Qual Device: LM4040D30IDBZR	Qual Device: TLV431AIDBZR
Assembly Site	NFME	NFME	NFME
Package Family	SOT	SOT	SOT
Flammability Rating	UL 94 V-0	UL 94 V-0	UL 94 V-0
Wafer Fab Supplier	SFAB	SFAB	SFAB
Wafer Process	JI2	JI2	OI

- QBS: Qual By Similarity
- Qual Devices qualified at LEVEL1-260CG: LM4040C50IDBZR, TLV431AIDBZR
- Qual Device LM4040D30IDBZR is qualified at LEVEL1-260C

#### **Qualification Results**

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: LM4040C50IDBZR	Qual Device: LM4040D30IDBZR	Qual Device: TLV431AIDBZR
AC	Autoclave 121C	96 Hours	1/77/0	1/77/0	1/77/0
ED	Electrical Characterization	Per Datasheet Parameters	1/30/0	1/30/0	1/30/0
FLAM	Flammability (IEC 695-2-2)		1/5/0	1/5/0	1/5/0
FLAM	Flammability (UL 94V-0)		1/5/0	1/5/0	1/5/0
FLAM	Flammability (UL-1694)		1/5/0	1/5/0	1/5/0
HAST	Biased HAST, 130C/85%RH	96 Hours	1/77/0	1/77/0	1/77/0
HTOL	Life Test, 150C	300 Hours	1/77/0	1/77/0	1/77/0
HTSL	High Temp. Storage Bake, 170C	420 Hours	1/77/0	1/77/0	1/77/0
LI	Lead Fatigue	Leads	1/22/0	1/22/0	1/22/0
LI	Lead Pull to Destruction	Leads	1/22/0	1/22/0	1/22/0
PD	Physical Dimensions		1/5/0	1/5/0	1/5/0
SD	Solderability	Pb-Free	1/22/0	1/22/0	1/22/0
TC	Temperature Cycle, - 65/150C	500 Cycles	1/77/0	1/77/0	1/77/0
WBP	Bond Strength	Wires	1/76/0	1/76/0	1/76/0
WBS	Ball Bond Shear	Wires	1/76/0	1/76/0	1/76/0

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- $\hbox{- The following are equivalent Temp Cycle options per JESD47: -} \hbox{-}55C/125C/700 Cycles and -} \hbox{-}65C/150C/500 Cycles$

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

#### Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

## **Qualification Report**

# Stand-alone delta Qual plan to add ATL431BQDBZR to the 3DBZ Qual List for NFME

Approve Date 03-Mar-2017

## **Product Attributes**

Attributes	Qual Device: ATL431BQDBZR	QBS Product Reference: ATL431BQDBZR	QBS Package Reference: LM4040C50IDBZR	QBS Package Reference: LM4040D30IDBZR	QBS Package Reference: TLV431AIDBZR	
Assembly Site	NFME	ASEWH	NFME	NFME	NFME	
Package Family	SOT	SOT	SOT	SOT	SOT	
Flammability Rating	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0	
Wafer Fab Supplier	SFAB	SFAB	SFAB	SFAB	SFAB	
Wafer Process	JI2	JI2	JI2	JI2	OI	

<sup>-</sup> QBS: Qual By Similarity

#### **Qualification Results**

Data Displayed as: Number of lots / Total sample size / Total failed

Test Name / Condition	Duration	Qual Device: ATL431BQDBZR	QBS Product Reference: ATL431BQDBZR	QBS Package Reference: LM4040C50IDBZR	QBS Package Reference: LM4040D30IDBZR	QBS Package Reference: TLV431AIDBZR
Autoclave 121C	96 Hours	1/77/0	-	1/77/0	1/77/0	1/77/0
Electrical Characterization	Per Datasheet Parameters	1/30/0	1/30/0	1/30/0	1/30/0	1/30/0
Flammability (IEC 695-2-2)		-	-	1/5/0	1/5/0	1/5/0
Flammability (UL 94V-0)		-	-	1/5/0	1/5/0	1/5/0
Flammability (UL- 1694)		-	-	1/5/0	1/5/0	1/5/0
Biased HAST, 130C/85%RH	96 Hours	1/77/0	-	1/77/0	1/77/0	1/77/0
ESD - HBM	2000 V	-	1/3/0	-	-	-
ESD - CDM	1500 V	-	1/3/0	-	-	-
Life Test, 150C	300 Hours	-	1/77/0	1/77/0	1/77/0	1/77/0
High Temp. Storage Bake, 170C	420 Hours	-	•	1/77/0	1/77/0	1/77/0
Lead Fatigue	Leads	-	-	1/22/0	1/22/0	1/22/0
Lead Pull to Destruction	Leads	-	-	1/22/0	1/22/0	1/22/0
Latch-up	(per JESD78)	-	1/6/0	-	-	-
Physical Dimensions		-	-	1/5/0	1/5/0	1/5/0
Solderability	Pb-Free	-	-	1/22/0	1/22/0	1/22/0
**T/C -65C/150C	500 Cycles	1/77/0	-	1/77/0	1/77/0	1/77/0
Bond Strength	Wires	1/5/0	-	1/76/0	1/76/0	1/76/0
Ball Bond Shear	Wires	1/5/0	-	1/76/0	1/76/0	1/76/0
	Condition  Autoclave 121C  Electrical Characterization  Flammability (IEC 695-2-2)  Flammability (UL 94V-0)  Flammability (UL-1694)  Biased HAST, 130C/85%RH  ESD - HBM  ESD - CDM  Life Test, 150C  High Temp. Storage Bake, 170C  Lead Fatigue  Lead Pull to Destruction  Latch-up  Physical Dimensions  Solderability  **T/C -65C/150C  Bond Strength	Autoclave 121C  Blectrical Characterization  Flammability (IEC 695-2-2)  Flammability (UL 94V-0)  Flammability (UL-1694)  Biased HAST, 130C/85%RH  ESD - HBM 2000 V  ESD - CDM 1500 V  Life Test, 150C 300 Hours  High Temp. Storage Bake, 170C  Lead Fatigue Leads  Lead Pull to Destruction  Latch-up (per JESD78)  Physical Dimensions  Solderability Pb-Free  **T/C -65C/150C 500 Cycles  Bond Strength Wires	Condition         Duration         ATL431BQDBZR           Autoclave 121C         96 Hours         1/77/0           Electrical Characterization         Per Datasheet Parameters         1/30/0           Flammability (IEC 695-2-2)          -           Flammability (UL 94V-0)          -           Flammability (UL 1694)          -           Biased HAST, 130C/85%RH         96 Hours         1/77/0           ESD - HBM         2000 V         -           ESD - CDM         1500 V         -           Life Test, 150C         300 Hours         -           High Temp.         Storage Bake, 170C         420 Hours         -           Lead Fatigue         Leads         -           Lead Pull to Destruction         Leads         -           Latch-up         (per JESD78)         -           Physical Dimensions         -         -           Solderability         Pb-Free         -           **T/C -65C/150C         500 Cycles         1/77/0           Bond Strength         Wires         1/5/0	Test Name / Condition	Test Name	Test Name

<sup>-</sup> Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

<sup>-</sup> Qual Device ATL431BQDBZR is qualified at LEVEL1-260C

<sup>-</sup> The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

<sup>-</sup> The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

#### Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com